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Electronic railway equipment – Train communication network (TCN) – Part 2-8: TCN conformance test

Matériel électronique ferroviaire – Réseau embarqué de train (TCN) – Partie 2-8: Essai de conformité TCN

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CONTENTS

FOREWORD 14
INTRODUCTION 16
1 Scope 17
2 Normative references 17
3 Terms, definitions, symbols and abbreviated terms 19
3.1 Terms and definitions 19
3.2 Symbols and abbreviated terms 19
4 Conformance test: approach, requirements and boundaries 20
4.1 Approach 20
4.1.1 General 20
4.1.2 Requirements 20
4.1.3 Requirements declaration statements for an Item Under Test (IUT) 22
4.2 Boundaries 23
4.2.1 General 23
4.2.2 Basic interconnection tests 24
4.2.3 Capability tests 24
4.2.4 Behaviour tests 25
4.2.5 Conformance resolution tests 25
4.2.6 Interpretation of clauses/subclauses and statements 26
4.2.7 Relation to interoperability 27
4.2.8 Relation to performance test 28
4.2.9 Definition of test cases 28
4.3 Conformance assessment process outline 29
4.3.1 General 29
4.3.2 Analysis of results, outcomes and verdicts 29
4.4 Mapping of IUT types to conformance test suites 30
5 Basic interface test 31
5.1 Scope 31
5.2 PICS pro-forma 31
5.2.1 General 31
5.2.2 PICS Tables 31
5.3 Testing framework 33
5.4 Physical layer test 33
5.4.1 Test purpose 33
5.4.2 Inspection of the Hardware Ethernet interface 33
5.4.3 Inspection of the mechanical Ethernet interface construction 33
5.4.4 Check of electrical Ethernet interface design 34
5.4.5 Check of Ethernet interface characteristics 34
5.4.6 Ethernet signal wave form test (IEEE standard) 34
5.4.7 Ethernet signal wave form test (amplified signals, optional) 34
5.4.8 Auto-Crossover- and Auto-Sensing-Test (only for switches) 34
5.5 Basic communication protocol test 35
5.5.1 Test purpose 35
5.5.2 Simple communication test 35
5.5.3 UDP rising payload test (only for End Devices) 35
5.5.4 TCP rising payload test (only for End Devices) 35

5.5.5 UDP long term test (only for End Devices) 35
5.6 Communication reliability tests 35
5.6.1 Test purpose 35
5.6.2 Burst immunity test 35
5.6.3 Ethernet interface isolation test 36
6 Conformance test of End Device 36
6.1 General 36
6.2 Related requirements 37
6.3 IUT and Test scope 37
6.4 PICS Pro-forma 38
6.4.1 General 38
6.4.2 PICS Tables 38
6.5 Testing framework 44
6.6 Test Suite IEC 61375-2-3 46
6.6.1 Test case TCCT23ED_001 46
6.6.2 Test case TCCT23ED_002 47
6.6.3 Test case TCCT23ED_003 49
6.6.4 Test case TCCT23ED_004 50
6.6.5 Test case TCCT23ED_005 51
6.6.6 Test case TCCT23ED_006 52
6.6.7 Test case TCCT23ED_007 53
6.6.8 Test case TCCT23ED_008 54
6.6.9 Test case TCCT23ED_009 55
6.7 Test Suite IEC 61375-2-5 55
6.7.1 Test case TCCT25ED_001 55
6.7.2 Test case TCCT25ED_002 56
6.7.3 Test case TCCT25ED_003 57
6.7.4 Test case TCCT25ED_004 58
6.7.5 Test case TCCT25ED_005 59
6.7.6 Test case TCCT25ED_006 60
6.7.7 Test case TCCT25ED_007 61
6.7.8 Test case TCCT25ED_008 62
6.7.9 Test case TCCT25ED_009 63
6.7.10 Test case TCCT25ED_010 64
6.8 Test Suite IEC61375-3-4 65
6.8.1 Test case TCCT34ED_001 65
6.8.2 Test case TCCT34ED_002 66
6.8.3 Test case TCCT34ED_003 67
6.8.4 Test case TCCT34ED_004 68
6.8.5 Test case TCCT34ED_005 69
6.8.6 Test case TCCT34ED_006 70
6.8.7 Test case TCCT34ED_007 71
6.8.8 Test case TCCT34ED_008 72
6.8.9 Test case TCCT34ED_009 73
6.8.10 Test case TCCT34ED_010 74
6.8.11 Test case TCCT34ED_011 75
6.8.12 Test case TCCT34ED_012 76
6.8.13 Test case TCCT34ED_013 77
6.8.14 Test case TCCT34ED_014 78

6.8.15 Test case TCCT34ED_015 79
6.8.16 Test case TCCT34ED_016 80
6.8.17 Test case TCCT34ED_017 81
6.8.18 Test case TCCT34ED_018 82
6.8.19 Test case TCCT34ED_019 83
6.8.20 Test case TCCT34ED_020 84
6.8.21 Test case TCCT34ED_021 85
6.8.22 Test caseTCCT34ED_022 86
7 Conformance test of ECN-equipped consist 86
7.1 Scope 86
7.2 Related requirements 86
7.3 PICS Pro-forma 86
7.3.1 General 86
7.3.2 PICS tables 87
7.4 Test cases 93
7.4.1 General 93
7.4.2 Recovery in case of network failure 94
7.4.3 IP address assignment via DHCP 96
7.4.4 Name (TCN-URI address) resolution via DNS 97
7.4.5 Switch basic functions 98
7.4.6 Priority levels 99
7.4.7 Ingress rate limiting 99
7.4.8 Egress rate shaping 100
7.4.9 Untagged/tagged frames 100
7.4.10 Switching and routing performance (optional) 101
7.4.11 NTP support 102
7.4.12 Switch management 102
7.4.13 Network management via SNMP 103
7.4.14 ECSP Interface (optional) 104
7.4.15 TTDB manager interface (optional) 105
7.4.16 DNS TCN interface (optional) 105
7.4.17 ETBN control interface (optional) 106
8 Conformance test of ETBN 106
8.1 Test scope 106
8.1.1 General 106
8.1.2 References 106
8.2 PICS Pro-forma 107
8.2.1 General 107
8.2.2 PICS tables 107
8.3 Test cases 115
8.3.1 Testing framework 115
8.3.2 Common Consist Topologies 118
8.3.3 Test Suite: ETB port settings 121
8.3.4 Test Suite: ETB Line Status and Link Aggregation management 123
8.3.5 Test Suite: TTDP HELLO format and content 130
8.3.6 Test Suite: Unicast address assignment and unicast routing 134
8.3.7 Test Suite: IP Multicast forwarding 137
8.3.8 Test Suite: TOPOLOGY frame format and basic functionality 148
8.3.9 Test Suite: Physical topology management and calculation 152

8.3.10 Test Suite: Logical connectivity management and calculation 156
8.3.11 Test Suite: Failing/loss of node(s) 162
8.3.12 Test Suite: Late/recovered node(s) 166
9 Conformance test of TRDP 172
9.1 General 172
9.2 Related requirements 173
9.3 SUT and Test scope 173
9.4 PICS Pro-forma 173
9.4.1 General 173
9.4.2 PICS Tables 173
9.5 Message Data test 187
9.5.1 Testing framework 187
9.5.2 Communication Model Test 188
9.5.3 Communication Pattern and Addressing Test 192
9.5.4 MD-PDU Test 204
9.5.5 TRDP Layer Service Primitives Test 206
9.5.6 TRDP Layer Filtering Rules Test 209
9.5.7 Caller TRDP Layer Test 214
9.5.8 Replier TRDP Layer Test 234
9.5.9 TCP Connection Handling Test 249
9.5.10 Message Data Echo Server Test 257
9.6 Process Data test 258
9.6.1 General 258
9.6.2 Test setup 258
9.6.3 PD push pattern test cases 259
9.6.4 PD pull pattern test cases 280
10 SDTv2 Conformance Test 298
10.1 Scope 298
10.1.1 General 298
10.1.2 Related requirements 298
10.1.3 Terms and abbreviations 298
10.1.4 Test scope 298
10.2 PICS Pro-forma 299
10.2.1 General 299
10.2.2 PICS Tables 299
10.3 SDSRC- SAFE DATA SOURCE 302
10.3.1 Purpose 302
10.3.2 Inspection of the SID Structure 302
10.3.3 Inspection of the Vital Data Packet 303
10.3.4 Exclusivity 304
10.3.5 SDSRC performance 305
10.4 SDSINK – SAFE DATA SINK 305
10.4.1 General 305
10.4.2 VDP sampling 305
10.4.3 VDP Integrity Check 305
10.4.4 Sink Time Supervision 306
10.4.5 Guard Time Supervision 306
10.4.6 Latency Monitoring 306
10.4.7 Channel Monitoring 307

10.4.8 SDTv2 Application Interface 307
10.4.9 Diagnostics and statistics 308
11 Conformance test of ETB-equipped consist 308
11.1 Scope 308
11.2 Abstract consist tester architecture 309
11.3 Consist test stages 311
11.4 PICS Pro-forma 311
11.4.1 General 311
11.4.2 PICS Tables 311
11.5 Related requirements 314
11.6 Testing configurations 314
11.6.1 General 314
11.6.2 Testing configuration TC1 315
11.6.3 Testing configuration TC2 316
11.6.4 Testing configuration TC3 316
11.7 Consist tester operation 317
11.7.1 General 317
11.7.2 ECS addressing 317
11.7.3 Test Stimuli 317
11.7.4 Expected result verification 320
11.7.5 Test execution timing considerations 321
11.8 Basic test 321
11.8.1 General 321
11.8.2 Test sequence for TTDB computation (middle consist, same orientation) 321
11.8.3 Test sequence for TTDB computation (middle consist, inverse orientation) 321
11.8.4 Test sequence for TTDB computation (end consist, no traction, same orientation) 322
11.8.5 Test sequence for TTDB computation (end consist, no traction, inverse orientation) 322
11.8.6 Test sequence for TTDB computation (end consist, traction, same orientation) 323
11.8.7 Test sequence for TTDB computation (end consist, traction, inverse orientation) 323
11.8.8 Test sequence for TTDB computation (train lengthening and shortening) 324
11.9 Leading test 325
11.9.1 General 325
11.9.2 Test sequence for Leading (TE1.1 leading, CuT middle) 326
11.9.3 Test sequence for Leading (TE2 leading, CuT middle) 326
11.9.4 Test sequence for Leading (TE1.1 leading, CuT end) 326
11.9.5 Test sequence for Leading (CuT leading direction 1) 327
11.9.6 Test sequence for Leading (CuT leading direction 2) 327
11.9.7 Test sequence for Leading (Leading double request) 328
11.9.8 Test sequence for Leading (Leading conflict) 329
11.10 Inhibit test 329
11.10.1 General 329
11.10.2 Test sequence for Inhibit (single) 329
11.10.3 Test sequence for Inhibit (multiple) 330
11.11 Confirmation/correction test 331
11.11.1 General 331

11.11.2 Test sequence for confirmation 332
11.11.3 Test sequence for correction single middle vehicle 333
11.11.4 Test sequence for correction two middle vehicles 333
11.11.5 Test sequence for correcting three middle vehicles 334
11.11.6 Test sequence for correcting end vehicle 335
11.12 Sleep mode function (optional) 336
11.12.1 General 336
11.12.2 Test sequence for sleep mode 336
11.13 Performance test 337
11.13.1 General 337
11.13.2 Inauguration performance 337
11.13.3 ECSP performance 338
11.14 End-to-End Communication 339
11.15 Multiple ETB test (option) 339
11.15.1 General 339
11.15.2 Conformance test 340
Annex A (normative) Test laboratory role and client role 341
A.1 Test laboratory and client role 341
A.1.1 General 341
A.1.2 Overview 341
A.2 Preparation for testing 342
A.2.1 General 342
A.2.2 General administrative steps 342
A.2.3 Agreement on test methods and selection of test suites 342
A.2.4 Exchange of documentation for conformance assessment 343
A.3 Test operation 344
A.3.1 General 344
A.3.2 Static conformance review 344
A.3.3 Selection of test cases and test parameterisation 345
A.3.4 Test campaign 345
A.4 Production of test reports 346
A.4.1 General 346
A.4.2 IUT conformance test report 347
A.4.3 Protocol conformance test report 347
Annex B (informative) Instructions for filling the PICS pro-forma 349
B.1 General 349
B.2 Abbreviations 349
B.3 Reference column 349
B.4 Supported subclause column 350
B.5 Supported capability column 350
B.6 Requirement column 350
B.7 Implementation column 350
B.8 Parameter values columns 351
B.8.1 Allowed min. 351
B.8.2 Default value 351
B.8.3 Allowed max. 351
B.8.4 Implemented value 351
Annex C (informative) Test instrumentation and dedicated test bed 352
C.1 Test instrumentation 352

C.1.1 Standard instrumentation – Test suites standard instrumentation ... 352
C.1.2 Test bed architecture ... 352
C.1.3 Consist tester specification ... 353
Bibliography ... 356

Figure 1 – Setup for burst immunity test ... 36
Figure 2 – End Device conformance testing process ... 37
Figure 3 – Consist topology and logical view of ECN ... 38
Figure 4 – Testing framework architecture ... 44
Figure 5 – General configuration for ECN-equipped consist test ... 94
Figure 6 – Example of configuration for the test of network redundancy ... 94
Figure 7 – Example of configuration of network redundancy with dual homing End Device interfaces ... 95
Figure 8 – Example of the configuration for the test of IP address assignment via DHCP ... 97
Figure 9 – Example of the configuration for the test of Name resolution via DNS ... 98
Figure 10 – Example of the configuration for the test of NTP support ... 102
Figure 11 – Example of the configuration for the test of Network management via SNMP ... 104
Figure 12 – TTS1 One ETBN connects with test system (monitoring) ... 116
Figure 13 – TTS2 single ETBN connects with test system (one side simulation) ... 116
Figure 14 – TTS3 Single ETBN connects with test system (both sides simulation) ... 117
Figure 15 – TTS4 Multiple ETBNs connect with test system (monitoring) ... 117
Figure 16 – TTS5 multiple ETBNs connect with test system (one side simulation) ... 118
Figure 17 – TTS6 Multiple ETBN connects with test system (both sides simulation) ... 118
Figure 18 – Consist topology with single ETBN and single CN ... 119
Figure 19 – Consist topology with multiple ETBNs, each connected to a separate CN ... 119
Figure 20 – Consist topology with a single ETBN connected to multiple CNs ... 119
Figure 21 – Consist topology with single CN with redundant ETBNs ... 120
Figure 22 – Consist topology with multiple CNs with redundant ETBNs ... 120
Figure 23 – Consist topology with multiple ETNs and CNs connected asymmetrically ... 120
Figure 24 – Setup to verify full duplex mode on ETB ports ... 122
Figure 25 – Example where IUT sends TOPOLOGY on line B (here X is B, Y is A) ... 124
Figure 26 – Simulating Logical line down for single line setup, by letting simulator stop sending HELLO on line X (line A) ... 125
Figure 27 – Simulating Logical line down for multiple line setup, by letting simulator stop sending HELLO on line X (here line B) ... 125
Figure 28 – Simulating one-way transmission error, by letting simulator send HELLO with recvXStatus FALSE (here recvBStatus FALSE) ... 126
Figure 29 – Testing correct handling of loss of HELLO transmitted by IUT, and loss of HELLO sent to IUT ... 127
Figure 30 – ETB line failover setup, the line where IUT initially forwards the data stream is referred to as 'X' (here line B) ... 128
Figure 31 – Topology for general multicast routing tests ... 138
Figure 32 – Topology for testing multicast with ETBN with multiple CNs ... 140
Figure 33 – Multicast test setup for consist with ECNs connected to different ETBNs ... 141

Figure 34 – Testing multicast with redundant ETBNs and single CN 142
Figure 35 – Multicast routing in consist with redundant ETBN and multiple CNs 144
Figure 36 – Testing multicast handling after reinauguation 145
Figure 37 – Test of multicast between local CNs on same ETBN when inaugurating 146
Figure 38 – Test of multicast between local CNs on different ETBNs when inaugurating 147
Figure 39 – Test ability to translate multicast destination address 147
Figure 40 – Testing transmission of connectivity vector 154
Figure 41 – Testing transmission of ETBN Vectors, number of ETBNs and ConnTableCrc32 155
Figure 42 – Testing loss of intermediate ETBNs/consists when inauguration is inhibited 162
Figure 43 – Test of losing intermediate ETBN in existence of "unknown intermediate" 163
Figure 44 – Test ability to handle loss of end node 164
Figure 45 – Test ability to handle loss of end node during lengthening 165
Figure 46 – Test ability to handle loss of end node when “late intermediate” is present 166
Figure 47 – Test environment 172
Figure 48 – System under Test 173
Figure 49 – TTS, IUT connected to the test system 259
Figure 50 – The switch in test topology 259
Figure 51 – TRDP telegram format 260
Figure 52 – Dataset of CONFTEST_PUSH_FORMAT 261
Figure 53 – Dataset of CONFTEST_UDP_PORT 262
Figure 54 – Dataset of CONFTEST_FCS 264
Figure 55 – Dataset of CONFTEST_FCS_REPLY 264
Figure 56 – Dataset of CONFTEST_PROTO_VERSION 266
Figure 57 – Dataset of CONFTEST_PROTO_VERSION_REPLY 266
Figure 58 – Dataset of CONFTEST_SIMU_TOPO 269
Figure 59 – Dataset of CONFTEST_IDU_TOPO 269
Figure 60 – Dataset of CONFTEST_DATA_LEN_1432 271
Figure 61 – Dataset of CONFTEST_DATA_LEN_0 271
Figure 62 – Dataset of CONFTEST_DATA_LEN_512 271
Figure 63 – Byte alignment test of 441 bytes length telegram data 273
Figure 64 – Byte alignment test of 442 bytes length telegram data 273
Figure 65 – Byte alignment test of 443 bytes length telegram data 273
Figure 66 – Dataset of CONFTEST_PUSH_FORMAT 275
Figure 67 – Dataset of CONFTEST_TIMEOUT_BEHAVIOR_ZERO 275
Figure 68 – Dataset of CONFTEST_TIMEOUT_BEHAVIOR_KEEP 276
Figure 69 – Dataset of CONFTEST_IP_FILTER 277
Figure 70 – Dataset of CONFTEST_IP_FILTER_REPLY 277
Figure 71 – DSCP(QOS) and TTL test telegram data 278
Figure 72 – Dataset of CONFTEST_REDUNDANT 279
Figure 73 – Dataset of CONFTEST_UNICAST 280
Figure 74 – Dataset of CONFTEST_PULL_ FORMAT_REQUEST 282
Figure 75 – Dataset of CONFTEST_PULL_ FORMAT_REPLY 283

Figure 76 – Dataset of CONFTEST_FCS_REQUEST 284
Figure 77 – Dataset of CONFTEST_FCS_REPLY 284
Figure 78 – Dataset of CONFTEST_PROTO_VERSION_REQUEST 286
Figure 79 – Dataset of CONFTEST_PROTO_VERSION_REPLY 286
Figure 80 – Dataset of CONFTEST_SIMU_TOPO 288
Figure 81 – Dataset of CONFTEST_IUT_TOPO 289
Figure 82 – Dataset of CONFTEST_IP_FILTER 290
Figure 83 – Dataset of CONFTEST_IP_FILTER_REPLY 290
Figure 84 – Dataset of CONFTEST_TIMEOUT_REQUEST_ZERO 292
Figure 85 – Dataset of CONFTEST_TIMEOUT_REPLY_ZERO 293
Figure 86 – Dataset of CONFTEST_TIMEOUT_REQUEST_KEEP 293
Figure 87 – Dataset of CONFTEST_TIMEOUT_REPLY_KEEP 294
Figure 88 – Dataset of CONFTEST_PULL_UNICAST 295
Figure 89 – Dataset of CONFTEST_REPLY COMID_REQUEST 296
Figure 90 – Dataset of CONFTEST_REPLY_COMID_REPLY 296
Figure 91 – Dataset of CONFTEST_REPLY_IPADDRESS_REQUEST 297
Figure 92 – Dataset of CONFTEST_REPLY_IPADDRESS_REPLY 297
Figure 93 – SDTv2 conformance testing process 298
Figure 94 – SID Generation 302
Figure 95 – Structure of a VDP 303
Figure 96 – VDP with detailed trailer structure 304
Figure 97 – Consist tester architecture 309
Figure 98 – ECSP proxy 310
Figure 99 – Testing configuration variants 315
Figure 100 – Testing configuration TC1 316
Figure 101 – Testing configuration TC2 316
Figure 102 – Testing configuration TC3 316
Figure 103 – TRDP ECSP control telegram 318
Figure C.1 – Coach tester architecture 353
Figure C.2 – Complete consist tester architecture 354
Figure C.3 – Multiple ETB tester architecture 355

Table 1 – Relation to interoperability 28
Table 2 – Relation to performance test 28
Table 3 – Test case categories 29
Table 4 – Mapping conformance testing suites to IUT types 31
Table 5 – Testing framework DEVICE description 45
Table 6 – Test case TCCT23ED_001 46
Table 7 – Test case TCCT23ED_002 47
Table 8 – Test case TCCT23ED_003 49
Table 9 – Test case TCCT23ED_004 50
Table 10 – Test case TCCT23ED_005 51
Table 11 – Test case TCCT23ED_006 52

Table 12 – Test case TCCT23ED_007 53
Table 13 – Test case TCCT23ED_008 54
Table 14 – Test case TCCT23ED_009 55
Table 15 – Test case TCCT25ED_001 55
Table 16 – Test case TCCT25ED_002 56
Table 17 – Test case TCCT25ED_003 57
Table 18 – Test case TCCT25ED_004 58
Table 19 – Test case TCCT25ED_005 59
Table 20 – Test case TCCT25ED_006 60
Table 21 – Test case TCCT25ED_007 61
Table 22 – Test case TCCT25ED_008 62
Table 23 – Test case TCCT25ED_009 63
Table 24 – Test case TCCT25ED_010 64
Table 25 – Test case TCCT34ED_001 65
Table 26 – Test case TCCT34ED_002 66
Table 27 – Test case TCCT34ED_003 67
Table 28 – Test case TCCT34ED_004 68
Table 29 – Test case TCCT34ED_005 69
Table 30 – Test case TCCT34ED_006 70
Table 31 – Test case TCCT34ED_007 71
Table 32 – Test case TCCT34ED_008 72
Table 33 – Test case TCCT34ED_009 73
Table 34 – Test case TCCT34ED_010 74
Table 35 – Test case TCCT34ED_011 75
Table 36 – Test case TCCT34ED_012 76
Table 37 – Test case TCCT34ED_013 77
Table 38 – Test case TCCT34ED_014 78
Table 39 – Test case TCCT34ED_015 79
Table 40 – Test case TCCT34ED_016 80
Table 41 – Test case TCCT34ED_017 81
Table 42 – Test case TCCT34ED_018 82
Table 43 – Test case TCCT34ED_019 83
Table 44 – Test case TCCT34ED_020 84
Table 45 – Test case TCCT34ED_021 85
Table 46 – Test caseTCCT34ED_022 86
Table 47 – Push pattern telegram test 259
Table 48 – Push pattern telegram format content 260
Table 49 – Telegram parameter of push pattern test 261
Table 50 – Destination UDP port test 262
Table 51 – Destination UDP port test telegram parameter 262
Table 52 – FCS check test 263
Table 53 – FCS check test telegram parameter 263
Table 54 – FCS check test reply telegram parameter 263

Table 55 – Protocol version test 265
Table 56 – Protocol version test telegram parameter 265
Table 57 – Protocol version test reply telegram parameter 265
Table 58 – Topology counter test 267
Table 59 – Simulator sending telegram parameter 268
Table 60 – IUT sending telegram parameter 269
Table 61 – Data length test 270
Table 62 – Data length test of 1 432 bytes length telegram parameters 270
Table 63 – Data length test of 0 byte length telegram parameters 270
Table 64 – Data length test of 512 bytes length telegram parameters 270
Table 65 – Byte alignment test 272
Table 66 – Byte alignment test of 441 bytes length telegram parameters 272
Table 67 – Byte alignment test of 442 bytes length telegram parameters 272
Table 68 – Byte alignment test of 443 bytes length telegram parameters 272
Table 69 – Timeout and validity test 274
Table 70 – Timeout and validity test telegram parameters 274
Table 71 – Timeout and validity test reply telegram parameters(ZERO mode) 274
Table 72 – Timeout and validity test reply telegram parameters(KEEP mode) 275
Table 73 – Receiving port IP filtering test 276
Table 74 – Receiving port IP filtering test telegram parameters 276
Table 75 – Receiving port IP filtering test reply telegram parameters 277
Table 76 – DSCP(QOS) and TTL test 278
Table 77 – DSCP(QOS) and TTL test telegram parameters 278
Table 78 – Redundancy test 279
Table 79 – Redundancy test telegram parameter 279
Table 80 – point to point test of push pattern 280
Table 81 – point to point test telegram parameter 280
Table 82 – Pull pattern telegram test 281
Table 83 – Pull pattern request telegram format content 281
Table 84 – Pull pattern reply telegram format content 281
Table 85 – Request telegram parameter of pull pattern test 282
Table 86 – Reply telegram parameter of pull pattern test 282
Table 87 – FCS check test 283
Table 88 – FCS check test request parameter 283
Table 89 – FCS check test reply parameter 284
Table 90 – Protocol version test 285
Table 91 – Protocol version test request telegram parameter 285
Table 92 – Protocol version test reply telegram parameter 285
Table 93 – Topology counter test 287
Table 94 – Requester topology counter test telegram parameter 288
Table 95 – Receiving port IP filtering test 289
Table 96 – Receiving port IP filtering test telegram parameters 289
Table 97 – Receiving port IP filtering test reply telegram parameters 290
Table 98 – Timeout and validity test 291
Table 99 – Timeout and validity test request telegram parameters (ZERO mode) 291
Table 100 – Timeout and validity test reply telegram parameters (ZERO mode) 291